ELSEVIER

Journal of Electron Spectroscopy and Related Phenomena 84 (1996) vii–viii

JOURNAL OF ELECTRON SPECTROSCOPY and Related Phenomena

Contents

Special Issue: Spectromicroscopy

Preface ... ix

Angle-resolved ultraviolet photoelectron microspectroscopy
G. Meister and A. Goldman (Kassel, Germany) ... 1

PISAM: a photon-induced scanning Auger microscope
M.R. Weiss, R. Fink, E. Umbach (Würzburg, Germany) and V. Wüstenhagen (Stuttgart, Germany) ... 9

The scanning soft X-ray microscope at Hasylab: imaging and spectroscopy of photoelectrons, photoluminescence, desorbed ions, reflected, scattered and transmitted light
J. Voss (Hamburg, Germany) ... 29

Thermal desorption of oxides on Si(100): a case study for the scanning photoelectron microscopy at MAX-LAB
U. Johansson, H. Zhang and R. Nyholm (Lund, Sweden) ... 45

X-ray spectromicroscopy of polymers and tribological surfaces at beamline X1A at the NSLS
H. Ade, A.P. Smith, H. Zhang, G.R. Zhuang (Raleigh, USA), J. Kirz (Stony Brook, NY, USA), E. Rightor (Freeport, TX, USA) and A. Hitchcock (Ontario, Canada) ... 53

ESCA Microscopy at ELETTRA: what it is like to perform spectromicroscopy experiments on a third generation synchrotron radiation source
M. Marsi, L. Casalis, L. Gregoratti, S. Günther, A. Kolmakov, J. Kovac, D. Lonza and M. Kiskinova (Trieste, Italy) ... 73

Soft X-ray spectromicroscopy development for materials science at the Advanced Light Source
T. Warwick, H. Padmore (Berkeley, CA, USA), H. Ade (Raleigh, NC, USA), A.P. Hitchcock (Ontario, Canada), Ed. G. Rightor (Freeport, TX, USA) and B.P. Tonner (Milwaukee, WI, USA) ... 85

Comparative magnetic-field imaging, electric-field imaging, and scanning Auger microscopy study of metal–matrix composites
Q. Ma, R.A. Rosenberg (Argonne, IL, USA), C. Kim, J. Grepstad, P. Pianetta (Stanford, CA, USA), T. Droubay, D. Dunham and B. Tonner (Milwaukee, WI, USA) ... 99

Spectromicroscopy and chemical imaging by laterally-resolved ESCA
C. Coluzza (Roma, Italy) and R. Moberg (Uppsala, Sweden) ... 109

Applications for small photoelectron emission microscopes
E.L. Montei, V.W. Ballarotto, M.E. Little and M.E. Kordesch (Athens, OH, USA) ... 129

Photoelectron spectromicroscopy with synchrotron radiation: applications to neurobiology
G. De Stasio and G. Margaritondo (Lausanne, Switzerland) ... 137

Photoelectron spectromicroscopy as a microchemical probe of high temperature superconductors
Y. Hwu (Taipei, Taiwan) ... 149

High-resolution X-ray absorption microspectroscopy of lamellar phases in natural ilmenite
T. Droubay, G. Mursky and G. Tonner (Milwaukee, WI, USA) ... 159

Recent progress in photoemission microscopy with emphasis on chemical and magnetic sensitivity
W. Swiech, G.H. Fecher, Ch. Ziethen, O. Schmidt, G. Schönhense (Mainz, Germany), K. Grzelakowski (Hünstetten, Germany), C.M. Schneider, R. Frömter, H.P. Oepen and J. Kirschner (Halle/Saale, Germany) ... 171

Imaging of magnetic domains by photoemission microscope
F.U. Hillebrecht, D. Spanke, J. Dresselhaus and V. Solinus (Düsseldorf, Germany) ... 189

Spectromicroscopy in a low energy electron microscopy
E. Bauer, C. Koziol, G. Lilienkamp and T. Schmidt (Clausthal-Zellerfeld, Germany) ... 201

A photoemission microscope with a hemispherical capacitor energy filter
B.P. Tonner, D. Dunham, T. Droubay and M. Pauli (Milwaukee, WI, USA) ... 211

SMART: a planned ultrahigh-resolution spectromicroscopy for BESSY II
R. Fink, M.R. Weiss, E. Umbach (Würzburg, Germany), D. Preikszas, H. Rose, R. Spehr, P. Hartel (Darmstadt, Germany), W. Engel, R. Degenhardt, R. Wichtendahl, H. Kuhlenbeck, W. Erlebach, K. Ihmann, R. Schlögl, H.-J. Freund, A.M. Bradshaw (Berlin, Germany), G. Lilienkemp, Th. Schmidt, E. Bauer (Clausthal-Zellerfeld, Germany) and G. Benner (Oberkochen, Germany) 231
Multipole WIEN-filter for a high-resolution X-PEEM
G.K.L. Marx, V. Gerheim and G. Schönhense (Mainz, Germany) 251

Author Index 263

Subject Index 265